

Degate

The stakes and challenges of silicon reverse engineering

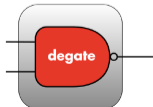
<https://www.degate.org>

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NEVERHACK

Bière Sécu Rennes,

May 14, 2024



Who am I?



Dorian Bachelot¹

- Currently a **Lead Product & Software Architect in Cybersecurity/AI** at NEVERHACK².
- Previously a master student doing **research on hardware reverse-engineering** at ESIEA³'s CNS laboratory.
- **Main maintainer of Degate** (since 2018).

¹<https://dorianb.net>

²<https://neverhack.com>

³<https://esiea.fr>



1 Chips Reverse Engineering

- Introduction

2 Degate

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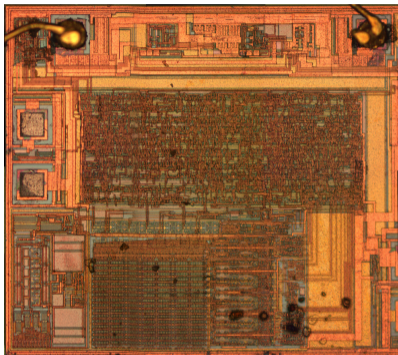
- 1 Chips Reverse Engineering
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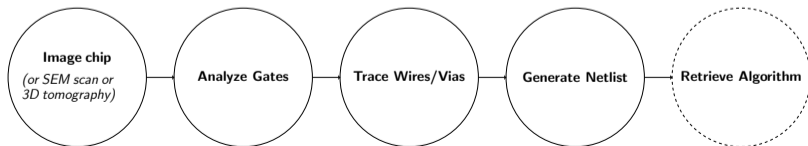
What is Silicon Chips RE?



Same idea than with software RE (from binary, to assembly and to code), chips RE go **from silicon, to images, to transistors, to gates, to netlist and to algorithm**.

With proper preparation and knowledge, we can go into silicon, **analyze transistors, retrieve gates/wires/vias and reconstruct implemented algorithms**. This can be used to **analyze old hardware, build software emulators, search for vulnerabilities and backdoors, break/test a protection, secret extraction or check intellectual property**.

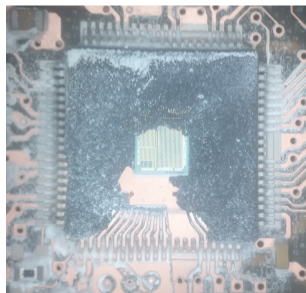
Used in IC industry for fault/failure detection & analysis, but not at the same scale.



How to Access Silicon?

Can be very costly (plasma & laser) and destructive... But also accessible with simpler methods (like chemical/mechanical). More on [4].

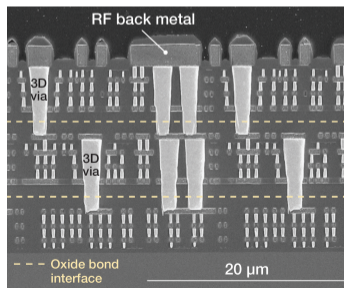
- 1 **Decapsulation** (heat, acid, mechanical, plasma, laser...)
- 2 **Delayering** (chemical, abrasive, laser, plasma...)
- 3 **Cleaning** (ultrasound, acid...)



[1]



[2]



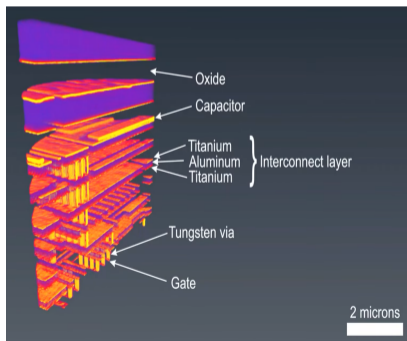
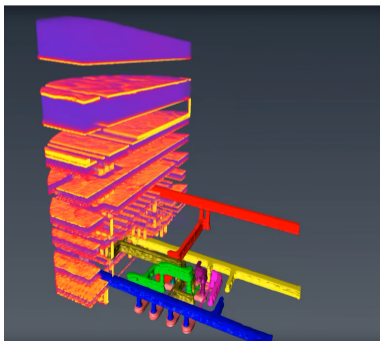
MIT



How to Retrieve Images?

Using each layer (invasive) or directly using the chip (non-invasive):

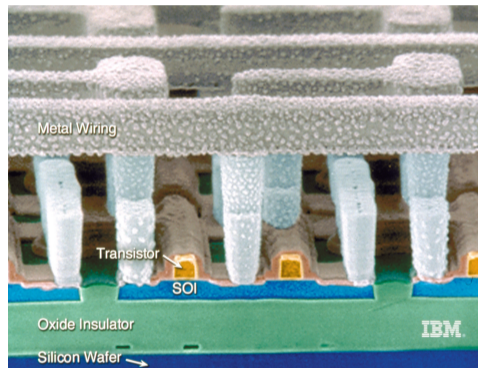
- Take very-high resolution images from **optical microscope** (basic, confocal) ;
- Scan from an **electron microscope** (SEM, TEM...) ;
- Generate a 3D model using **electron tomography** ;



How to Perform the Analysis?

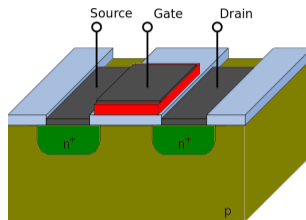
Overview:

- 1 Choose a **zone of interest**,
- 2 Identify each **gate type**, annotate, and place in a "**gate library**",
- 3 Find other **gates instance** from gate library,
- 4 Link gates by tracing **wires and vias**,
- 5 Export to **netlist** (e.g. by translating each gate to VHDL/Verilog code).



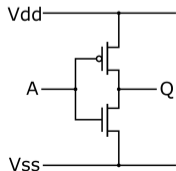
How to identify a transistor?

- 1 Search, at transistor layer, for **doped zones**.
- 2 Spot the **zebras**.
- 3 Use logic to identify the **type of each transistor** (e.g. PMOS are bigger to compensate with lower hole mobility).
- 4 Search for **wires** (to identify inputs and outputs).

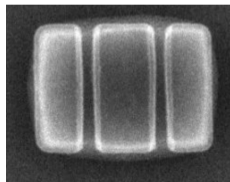


■ Polysilicon ■ Silicon dioxide
■ Metal

(NMOS, Wikipedia)



(Inverter, Wikipedia)



(PMOS [10])



How to Identify a Gate?



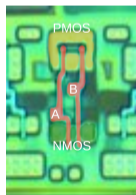
Transistor layer



Logic layer



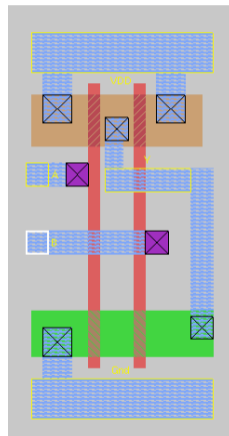
Metal layer



P & N zones and 2 inputs



V+ & V-, and output



[7] ⇒

NAND gate!



A	B	Y
0	0	1
1	0	1
0	1	1
1	1	0



How to Retrieve the Netlist from Analyzed Gates?

```

module jsrflipflop(q,qbar,clk,rst,sr);
  output reg q;
  output qbar;
  input clk, rst;
  input [1:0] sr;

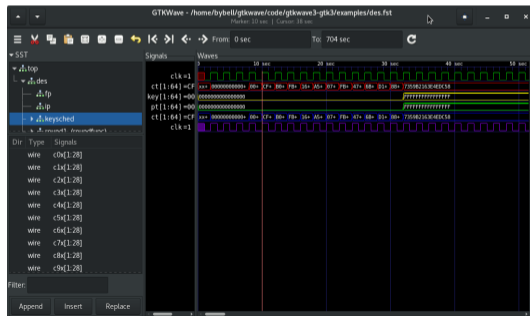
  assign qbar = ~q;

  always @(posedge clk)
  begin
    if (rst)
      q <= 0;
    else
      case(sr)
        2'b00: q <= q;
        2'b01: q <= 0;
        2'b10: q <= 1;
        2'b11: q <= 1'bx;
      endcase
    end
  end
endmodule

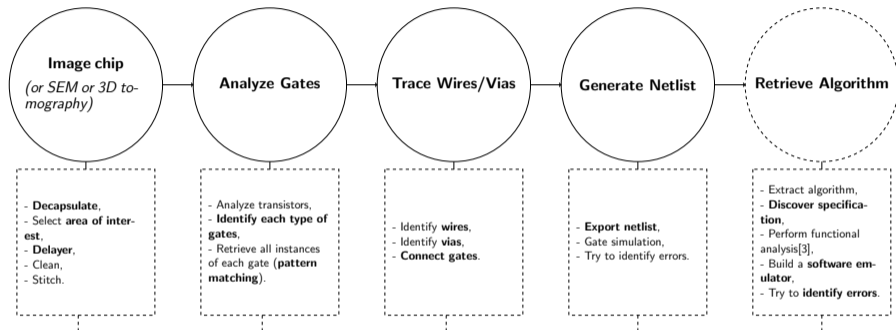
```

- Each gate can be described with **hardware description language (HDL)**, like **Verilog** or **VHDL**.
- **Wires & vias** can also be described.
- That's all we need to **obtain the netlist!**

We can, from HDL, **simulate the extracted netlist** and **find incoherence** (*example with gtkwave below*):



To Summarize



[2]



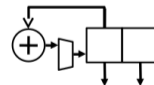
[2]



[2]

```

<?xml version="1.0"
<gate-library>
<gate description=
<ports>
<port id="0" nam
<port id="1" nam[2]
  
```



[2]



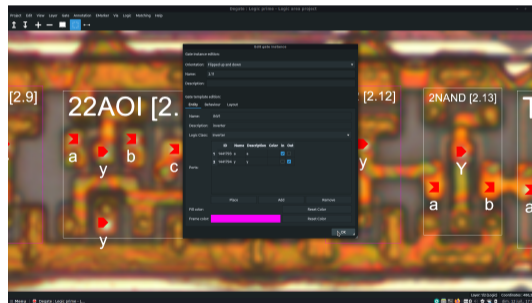
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Introduction

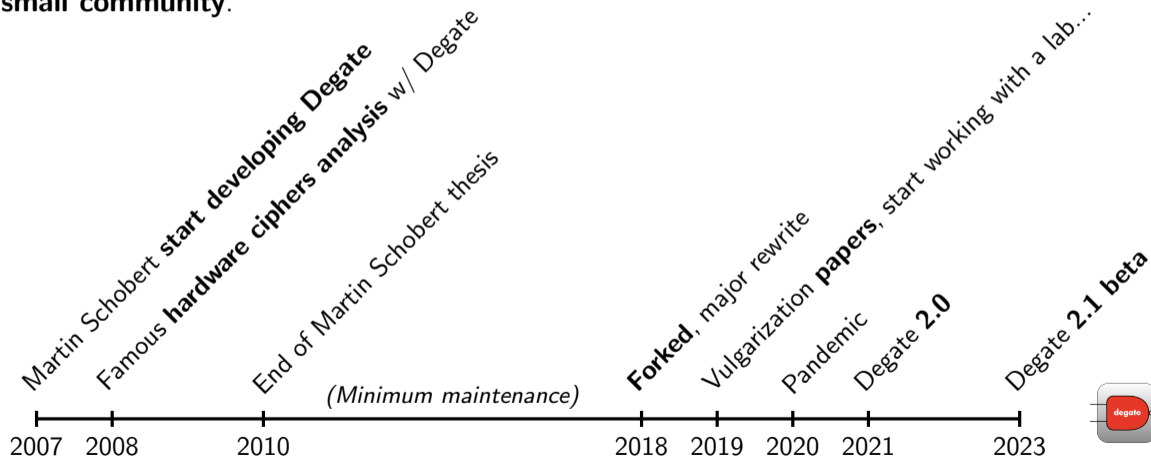
Degate is a multi-platform software for semi-automatic **Very-Large-Scale Integration (VLSI) chips reverse engineering** of digital logic in chips.

- ~70k LoC
- Supports Mac, Linux & Windows,
- Qt based,
- Multi-language support,
- Gate definition,
- Gate template, via & wire matching,
- Rule checks,
- ...



History

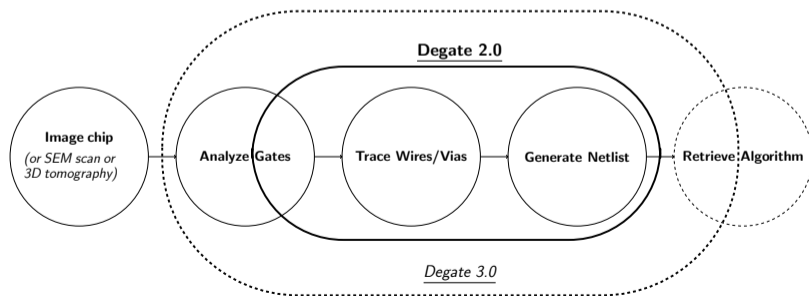
A long story, with **technical debt** and **major IC evolution** (in transistor count), along with a **small community**.



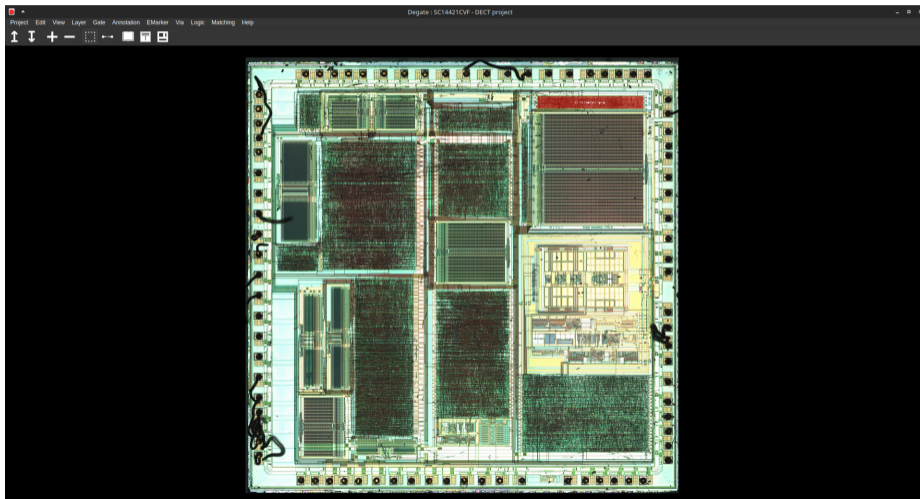
Usage

Degate help to reverse **VLSI chips** by creating an analyzed **gate library**, doing **template matching** to find gates instances from this library, **matching wires & vias**, **exporting netlist** and **navigating really huge images**.

Focus on **modern ICs** with **standard cells**, and supports **any 2D capture/imaging method** (SEM, optical...).



Small Demonstration

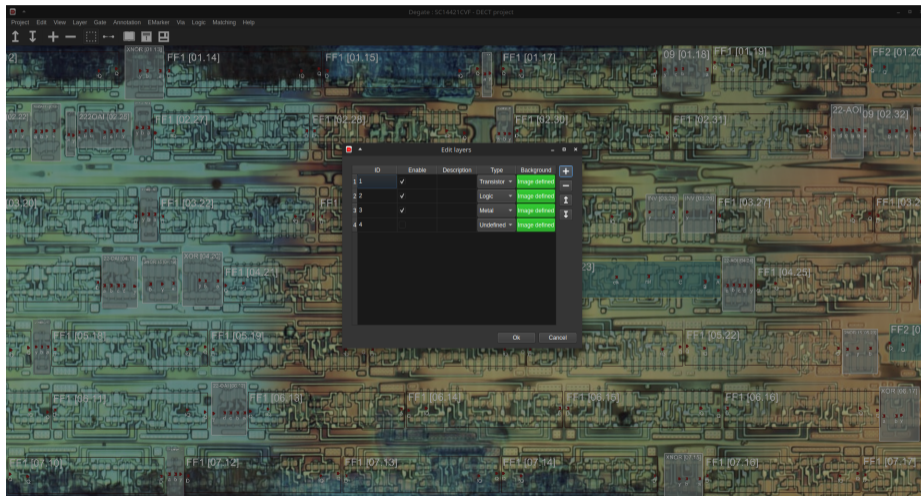


Overview of the chip, for zone of interest selection.

A sub-project can then be created on the zone of interest, and specific layers can be added (independent from the rest).



Small Demonstration

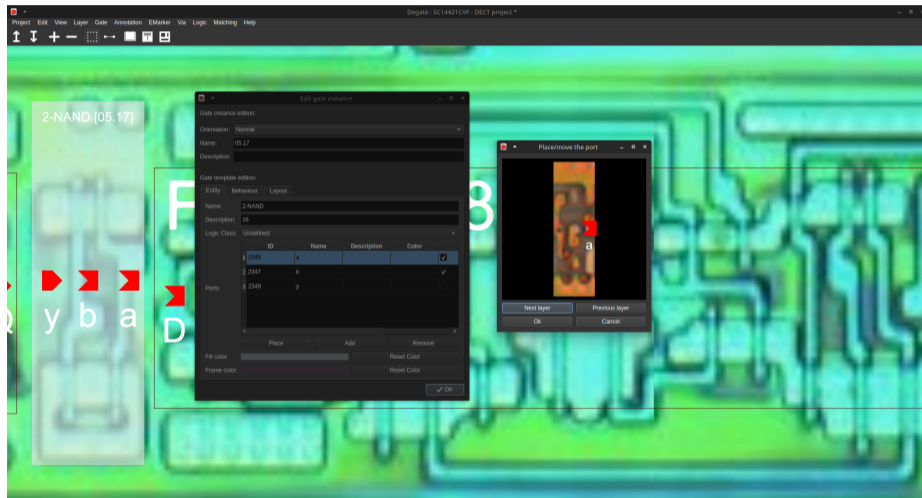


Each sub-project can contain multiple layers (pre-aligned images).

Two project mode: 1. For smaller images, will convert each images in Degate's format (for fast access) and 2. New (WIP, beta) mode for huge images (load only partial tiles in RAM, and doesn't change/import initial file).



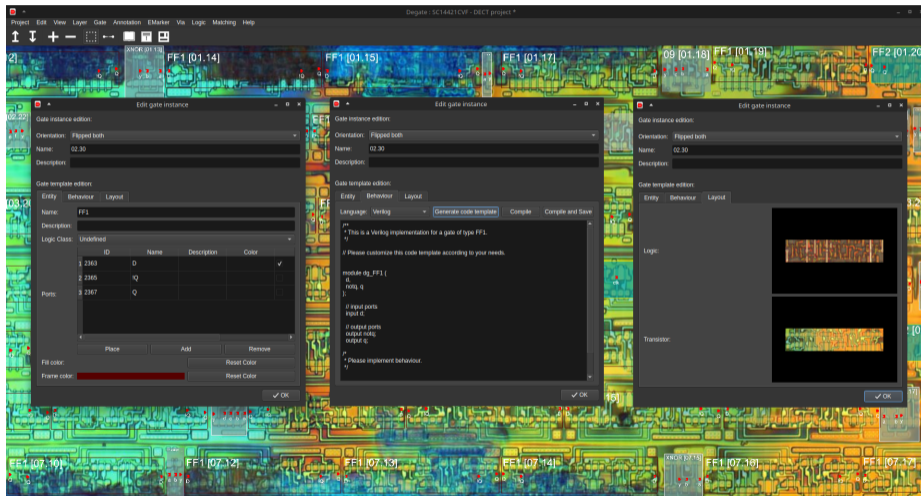
Small Demonstration



Each gate can be described with VHDL/Verilog, have a list of port (placed on image), a type associated etc.



Small Demonstration



Each identified gate (from the gate library) can be matched manually or using template matching algorithms.



Small Demonstration

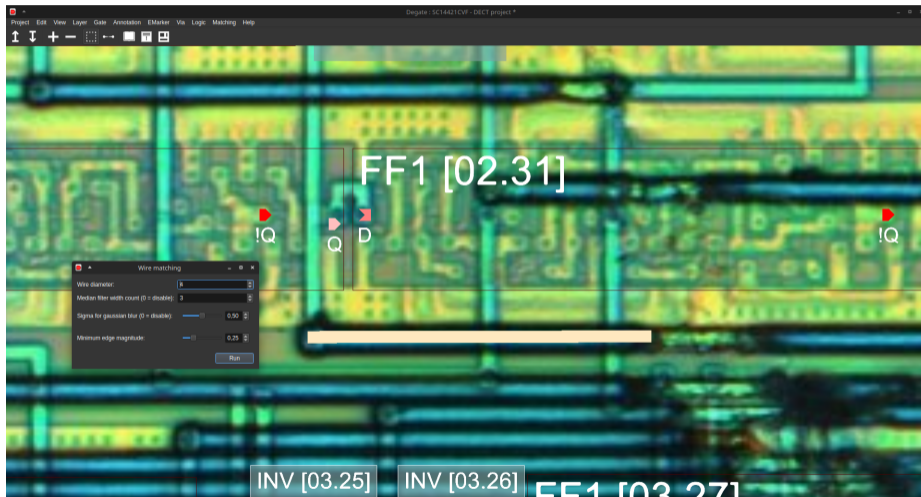


Template matching (will soon be ported to OpenCV) will use gate library to automate gate identification.

Currently it uses normalized cross-correlation (with some more steps).



Small Demonstration



Wire matching, and specifically port interconnection, is the real challenge (and very error prone).

Currently it uses zero crossing edge detection.



Small Demonstration

The screenshot displays the Degate tool interface for a project named "SC14421CVF - DECT project". The main window shows a circuit visualization with a color-coded layout. A "Rule violations" window is open, listing 32 violations. The violations are categorized by Layer and Class, with a Severity of "error" for all. The descriptions indicate various issues such as unconnected ports and out-ports connected to other out-ports.

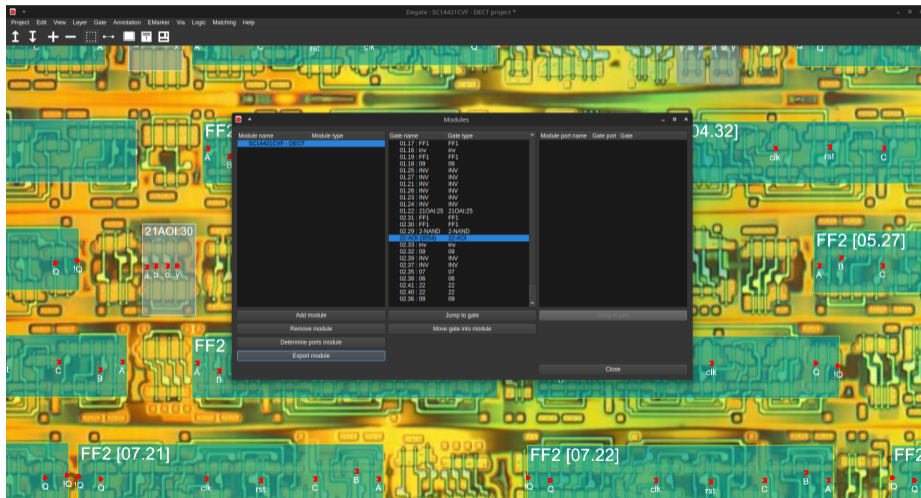
Layer	Class	Severity	Description
1	open_port	warning	Port a (inv. gate=7) is unconnected.
2	open_port	warning	Port y (inv. gate=7) is unconnected.
3	open_port	warning	Port a (inv. gate=10) is unconnected.
4	open_port	warning	Port y (inv. gate=10) is unconnected.
5	open_port	warning	Port d (22-ACL, gate=13) is unconnected.
6	open_port	warning	Port c (22-ACL, gate=13) is unconnected.
7	open_port	warning	Port b (22-ACL, gate=13) is unconnected.
8	open_port	warning	Port a (22-ACL, gate=13) is unconnected.
9	open_port	warning	Port y (22-ACL, gate=13) is unconnected.
10	net_outputs_connected	error	Out-Port 04.29 : y (20) is connected with other out-ports.
11	net_outputs_connected	error	Out-Port 04.34 : Q (FF1) is connected with other out-ports.
12	net_outputs_connected	error	Out-Port 04.34 : Q (FF2) is connected with other out-ports.
13	net_outputs_connected	error	Out-Port 04.31 : y (2-NAND) is connected with other out-ports.
14	net_outputs_connected	error	Out-Port 04.14 : Q (FF1) is connected with other out-ports.
15	net_outputs_connected	error	Out-Port 05.20 : Q (FF1) is connected with other out-ports.
16	net_outputs_connected	error	Out-Port 03.23 : Q (FF1) is connected with other out-ports.
17	net_outputs_connected	error	Out-Port 02.13 : Q (FF1) is connected with other out-ports.
18	net_outputs_connected	error	Out-Port 01.15 : Q (FF1) is connected with other out-ports.
19	net_outputs_connected	error	Out-Port 04.22 : Q (FF1) is connected with other out-ports.
20	net_outputs_connected	error	Out-Port 04.05 : Q (FF1) is connected with other out-ports.
21	net_outputs_connected	error	Out-Port 04.01 : Q (FF1) is connected with other out-ports.
22	net_outputs_connected	error	Out-Port 04.03 : Q (FF1) is connected with other out-ports.
23	net_outputs_connected	error	Out-Port 04.04 : Q (FF1) is connected with other out-ports.
24	net_outputs_connected	error	Out-Port 04.02 : Q (FF1) is connected with other out-ports.
25	net_outputs_connected	error	Out-Port 04.29 : Q (FF2) is connected with other out-ports.
26	net_outputs_connected	error	Out-Port 04.33 : Q (FF2) is connected with other out-ports.
27	net_outputs_connected	error	Out-Port 04.33 : Q (FF2) is connected with other out-ports.
28	net_outputs_connected	error	Out-Port 04.32 : Q (FF2) is connected with other out-ports.
29	net_outputs_connected	error	Out-Port 04.21 : Q (FF2) is connected with other out-ports.
30	net_outputs_connected	error	Out-Port 04.27 : Q (FF1) is connected with other out-ports.
31	net_outputs_connected	error	Out-Port 04.25 : Q (FF1) is connected with other out-ports.
32	net_outputs_connected	error	Out-Port 01.08 : Q (FF1) is connected with other out-ports.

The circuit visualization shows several components labeled: FF2 [07.21], FF2 [07.22], FF2 [05.27], and FF2. Red dots indicate the locations of the violations on the circuit.

Helpers are available, like rudimentary (but to be improved) rule checking (e.g. for coherency).



Small Demonstration



Everything can be organized in "module", exported individually (in Verilog/VHDL), etc... "Divide et impera".



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References I

- [1] Mirko Holler, Manuel Guizar-Sicairos, Esther H. R. Tsai, Roberto Dinapoli, Elisabeth Müller, Oliver Bunk, Jörg Raabe, and Gabriel Aeppli.
High-resolution non-destructive three-dimensional imaging of integrated circuits.
Nature, 543(7645):402–406, March 2017.
- [2] Starbug Karsten Nohl.
Pacsec silicon conference.
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- [3] Nils Albartus Ran Ginosara Avi Mendelson Leonid Azriel, Julian Speith and Christof Paar.
Azriel and julian speith and nils albartus and ran ginosara and avi mendelson and christof paar.
Cryptography ePrint Archive, Paper 2021/1278, 2021.



References II

- [4] John McMaster.
Siliconpr0n, <https://siliconpr0n.org/>.
- [5] Karsten Nohl, David Evans, and Henryk Plotz.
Reverse-Engineering a Cryptographic RFID Tag.
page 9.
- [6] Martin Schobert.
Gnu software degate.
Webpage: <http://www.degate.org>.
- [7] Berlin Security Research Labs.
Siliconzoo, <http://siliconzoo.org>.



References III

- [8] Ken Shirriff.
Ken shirriff's blog, <https://www.righto.com/>.
- [9] Mikhail Svarichevsky.
Zeptobars, <https://zeptobars.com/en/>.
- [10] Zonenberg Andrew Yener Bulent.
Csci 4974/6974 hardware reverse engineering, 2014.



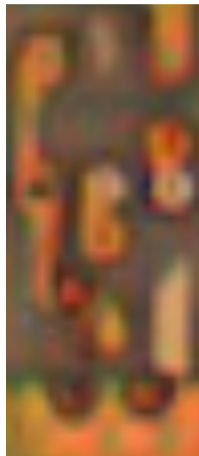
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Which gate is this?



Transistor layer



Logic layer



Metal layer

